

# SW4N40DC-VB TO252 Datasheet Power MOSFET

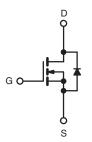
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	400	400				
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	2.1				
Q <sub>g</sub> (Max.) (nC)	20	20				
Q <sub>gs</sub> (nC)	3.3	3.3				
Q <sub>gd</sub> (nC)	11	11				
Configuration	Sing	Single				

#### **FEATURES**

- Dynamic dV/dt rating
- Repetitive avalanche rated
- Available in tape and reel
- · Fast switching
- Ease of paralleling







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	400	V	
Gate-Source Voltage			$V_{GS}$	± 20	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C		4.0		
		T <sub>C</sub> = 100 °C	I <sub>D</sub>	2.6	Α	
Pulsed Drain Current a			I <sub>DM</sub>	15		
Linear Derating Factor				0.33	W/°C	
Linear Derating Factor (PCB Mount) e				0.020		
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	160	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	4.0	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	4.8	mJ	
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	D	46	W	
Maximum Power Dissipation (PCB Mount)e	T <sub>A</sub> =	= 25 °C P <sub>D</sub>		2.5	l vv	
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	4.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	- °C	
Soldering Recommendations (Peak Temperature) d	for 10 s			260		

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 29 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 3.1 A (see fig. 12).
- c.  $I_{SD} \leq 3.1$  A,  $dI/dt \leq 65$  A/µs,  $V_{DD} \leq V_{DS}$ ,  $T_{J} \leq 150$  °C.
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	-	110	
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	R <sub>thJA</sub>	-	-	50	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	-	3.0	

#### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					I.	•	•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	400	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I <sub>D</sub> = 1 mA	-	0.51	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		= 400 V, V <sub>GS</sub> = 0 V V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	25 250	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 320 \text{ V}$	$I_D = 1.9 \text{ A}^b$	_	2.1	-	Ω
Forward Transconductance	9fs		= 50 V, I <sub>D</sub> = 1.9 A	1.7	-	_	S
Dynamic	313	- 553					1
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	_	350	-	
Output Capacitance	C <sub>oss</sub>	-	$V_{GS} = 0 \text{ V},$ $V_{DS} = -25 \text{ V},$	-	120	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>		.0 MHz, see fig. 5	-	47	-	
Total Gate Charge	Qg			-	-	20	
Gate-Source Charge	Q <sub>qs</sub>	V <sub>GS</sub> = 10 V	$I_D = 3.3 \text{ A}, V_{DS} = 320 \text{ V},$	-	-	3.3	nC
Gate-Drain Charge	Q <sub>qd</sub>	see fig. 6 and 13 b		-	-	11	
Turn-On Delay Time	t <sub>d(on)</sub>			-	10	-	
Rise Time	t <sub>r</sub>	$V_{DD} = 200 \text{ V, } I_D = 3.3 \text{ A,}$ $R_g = 18 \ \Omega, \ R_D = 56 \ \Omega, \ \text{see fig. } 10^{\text{ b}}$		-	14	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	30	-	
Fall Time	t <sub>f</sub>			-	13	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.1	_
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	12	A
Body Diode Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C},  I_S = 3.1  \text{A},  V_{GS} = 0  \text{V}^{ \text{b}}$		-	-	1.6	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	- T <sub>J</sub> = 25 °C, I <sub>F</sub> = 3.3 A, dI/dt = 100 A/μs b		-	270	600	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	1.4	3.0	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	ırn-on time is negligible (turn	on is dor	ninated b	y L <sub>S</sub> and	L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

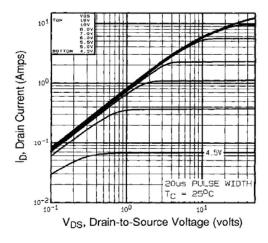


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

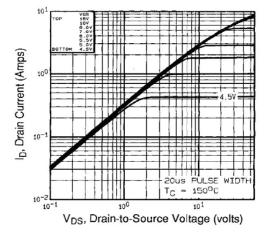


Fig. 2 - Typical Output Characteristics,  $T_C$  = 150  $^{\circ}C$ 

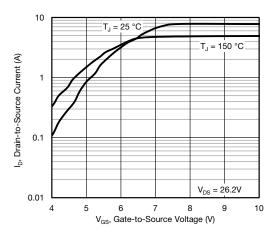


Fig. 3 - Typical Transfer Characteristics

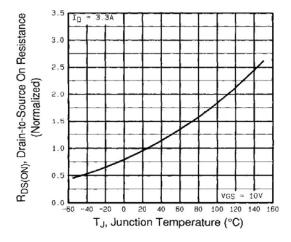


Fig. 4 - Normalized On-Resistance vs. Temperature



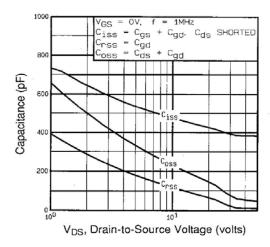


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

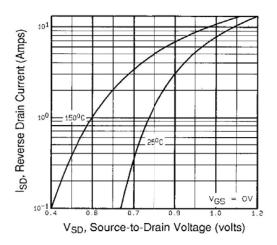


Fig. 7 - Typical Source-Drain Diode Forward Voltage

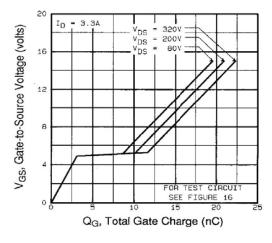


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

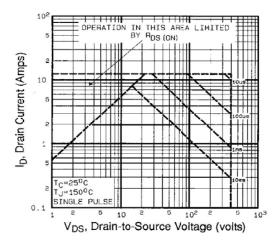
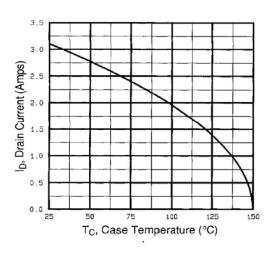


Fig. 8 - Maximum Safe Operating Area





 $V_{DS}$   $V_{DS}$  V

Fig. 10a - Switching Time Test Circuit

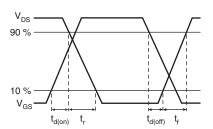


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10b - Switching Time Waveforms

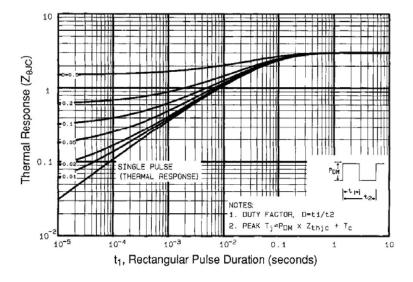


Fig. 10 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



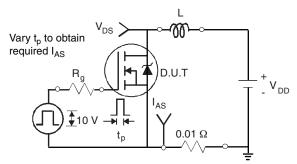


Fig. 12a - Unclamped Inductive Test Circuit

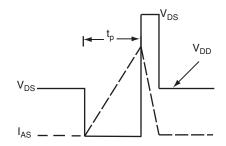


Fig. 12b - Unclamped Inductive Waveforms

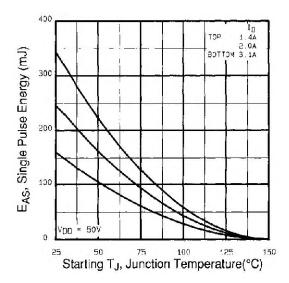


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

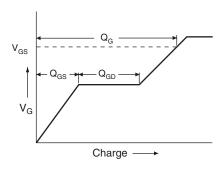


Fig. 13a - Basic Gate Charge Waveform

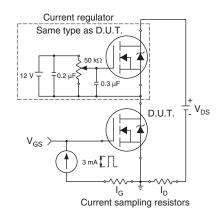
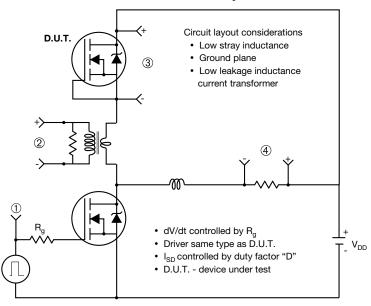


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



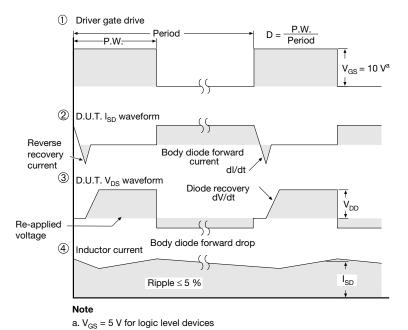
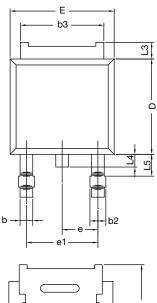
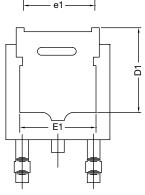


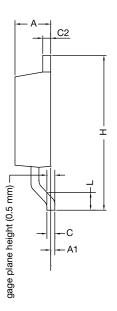
Fig. 14 - For N-Channel



## **TO-252AA Case Outline**







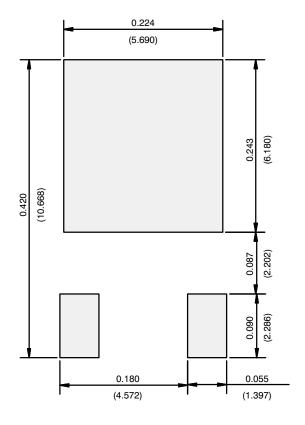
	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	4.10	-	0.161	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.01	1.52	0.040	0.060	
ECN: T16-0236-Rev. P, 16-May-16 DWG: 5347					

### Notes

• Dimension L3 is for reference only.



## **RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)**



Recommended Minimum Pads Dimensions in Inches/(mm)



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